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N-channel 640 V, 5 A, 0.88 Ω typ., MDmesh™ II Power MOSFET in a DPAK package

Datasheet - production data

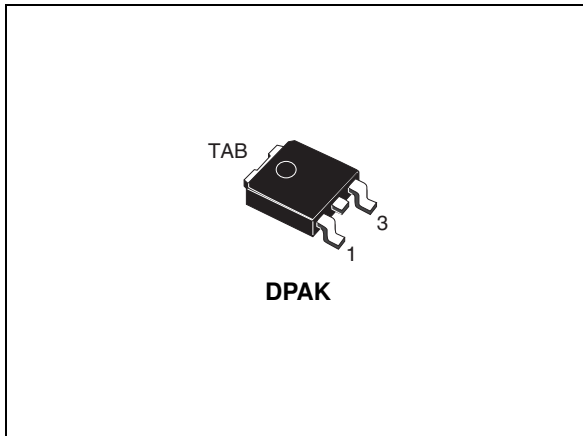
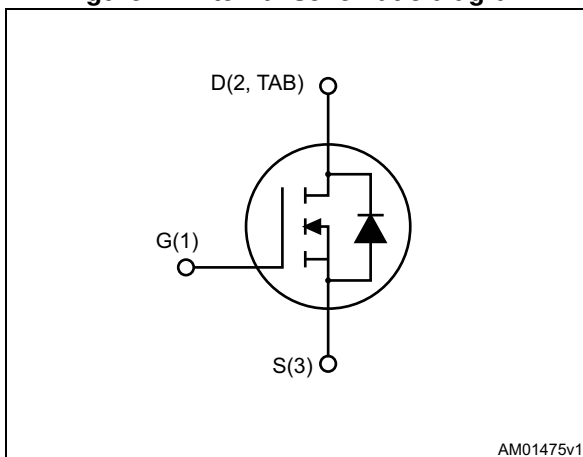


Figure 1. Internal schematic diagram



Features

| Order code | V_{DS} | $R_{DS(on)}$ max. | I_D |
|------------|----------|-------------------|-------|
| STD7NM64N | 640 V | 1.05 Ω | 5 A |

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

- Switching applications

Description

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

Table 1. Device summary

| Order code | Marking | Packages | Packaging |
|------------|---------|----------|---------------|
| STD7NM64N | 7NM64N | DPAK | Tape and reel |

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1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|-------------|------------------|
| V_{DS} | Drain-source voltage | 640 | V |
| V_{GS} | Gate-source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$ | 5 | A |
| I_D | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 3 | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 20 | A |
| P_{TOT} | Total dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 60 | W |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| $dv/dt^{(3)}$ | MOSFET dv/dt ruggedness | 50 | V/ns |
| T_{stg} | Storage temperature | - 55 to 150 | $^\circ\text{C}$ |
| T_j | Max. operating junction temperature | 150 | $^\circ\text{C}$ |

1. Pulse width limited by safe operating area
2. $I_{SD} \leq 5\text{ A}$, $di/dt \leq 400\text{ A}/\mu\text{s}$, $V_{DS(\text{peak})} < V_{(BR)DSS}$
3. $V_{DS} \leq 512\text{ V}$

Table 3. Thermal data

| Symbol | Parameter | Value | Unit |
|----------------------------|--------------------------------------|-------|---------------------------|
| $R_{thj\text{-case}}$ | Thermal resistance junction-case max | 2.08 | $^\circ\text{C}/\text{W}$ |
| $R_{thj\text{-pcb}}^{(1)}$ | Thermal resistance junction-pcb max | 50 | $^\circ\text{C}/\text{W}$ |

1. When mounted on 1 inch² FR-4, 2 Oz copper board

Table 4. Thermal data

| Symbol | Parameter | Value | Unit |
|----------|--|-------|------|
| I_{AR} | Avalanche current, repetitive or not-repetitive (pulse width limited by T_j max) | 2 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{ V}$) | 119 | mJ |

2 Electrical characteristics

($T_C = 25\text{ °C}$ unless otherwise specified).

Table 5. On /off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|---|---|------|------|-----------|---------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage ($V_{GS} = 0$) | $I_D = 1\text{ mA}$ | 640 | | | V |
| I_{DSS} | Zero gate voltage drain current | $V_{DS} = 640\text{ V}$ | | | 1 | μA |
| | | $V_{DS} = 640\text{ V}, T_C = 125\text{ °C}$ | | | 100 | μA |
| I_{GSS} | Gate-body leakage current ($V_{DS} = 0$) | $V_{GS} = \pm 20\text{ V}$ | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}, I_D = 250\text{ }\mu\text{A}$ | 2 | 3 | 4 | V |
| $R_{DS(on)}$ | Static drain-source on-resistance | $V_{GS} = 10\text{ V}, I_D = 2.5\text{ A}$ | | 0.88 | 1.05 | Ω |

Table 6. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|----------------------------|-------------------------------|---|------|------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 50\text{ V}, f = 1\text{ MHz}, V_{GS} = 0$ | - | 363 | - | pF |
| C_{oss} | Output capacitance | | - | 24.6 | - | pF |
| C_{rss} | Reverse transfer capacitance | | - | 1.1 | - | pF |
| $C_{oss\text{ eq.}}^{(1)}$ | Equivalent output capacitance | $V_{DS} = 0\text{ to }480\text{ V}, V_{GS} = 0$ | - | 130 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1\text{ MHz}, I_D = 0$ | - | 5.4 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 480\text{ V}, I_D = 5\text{ A}, V_{GS} = 10\text{ V}$ (see Figure 14) | - | 14 | - | nC |
| Q_{gs} | Gate-source charge | | - | 2.7 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 7.7 | - | nC |

1. $C_{oss\text{ eq.}}$ is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DS} .

Table 7. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max | Unit |
|--------------|---------------------|--|------|------|-----|------|
| $t_{d(on)}$ | Turn-on delay time | $V_{DD} = 300\text{ V}$, $I_D = 2.5\text{ A}$, $R_G = 4.7\ \Omega$, $V_{GS} = 10\text{ V}$ (see Figure 13) | - | 7 | - | ns |
| t_r | Rise time | | - | 10 | - | ns |
| $t_{d(off)}$ | Turn-off-delay time | | - | 26 | - | ns |
| t_f | Fall time | | - | 12 | - | ns |

Table 8. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-----------------|-------------------------------|--|------|------|------|---------------|
| I_{SD} | Source-drain current | | - | | 5 | A |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 20 | A |
| $V_{SD}^{(2)}$ | Forward on voltage | $I_{SD} = 5\text{ A}$, $V_{GS} = 0$ | - | | 1.3 | V |
| t_{rr} | Reverse recovery time | $I_{SD} = 5\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$ (see Figure 18) | - | 213 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 1.5 | | μC |
| I_{RRM} | Reverse recovery current | | - | 14 | | A |
| t_{rr} | Reverse recovery time | $I_{SD} = 5\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 60\text{ V}$, $T_j = 150\text{ }^\circ\text{C}$ (see Figure 18) | - | 265 | | ns |
| Q_{rr} | Reverse recovery charge | | - | 1.8 | | μC |
| I_{RRM} | Reverse recovery current | | - | 14 | | A |

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

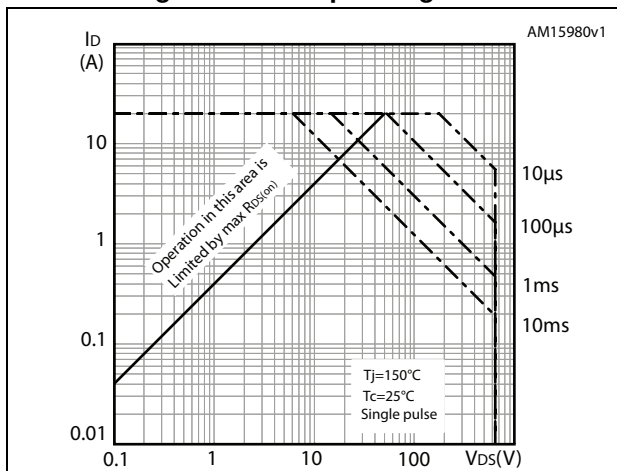


Figure 3. Thermal impedance

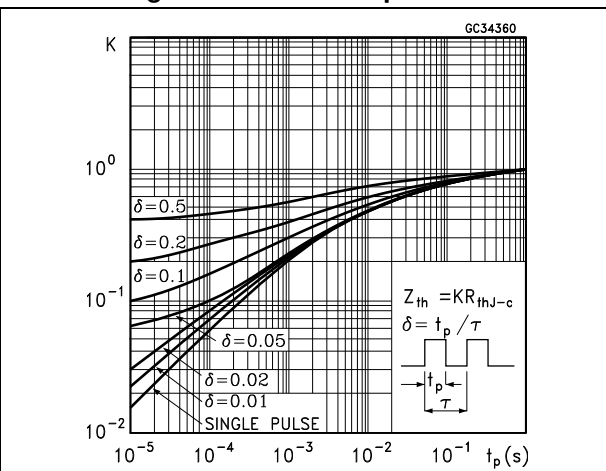


Figure 4. Output characteristics

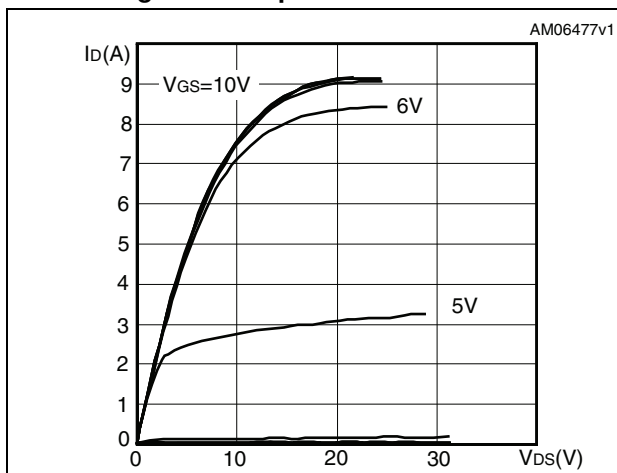


Figure 5. Transfer characteristics

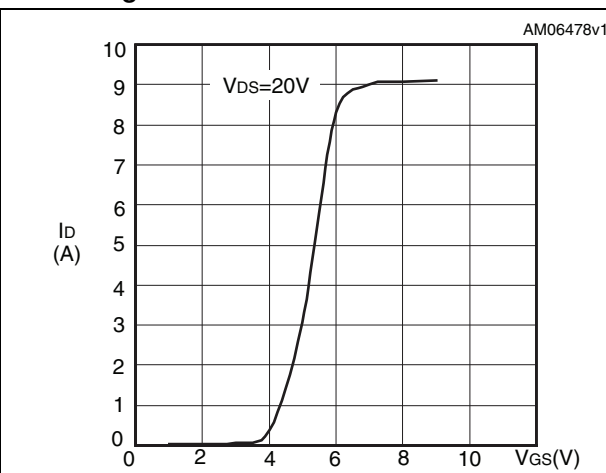


Figure 6. Gate charge vs gate-source voltage

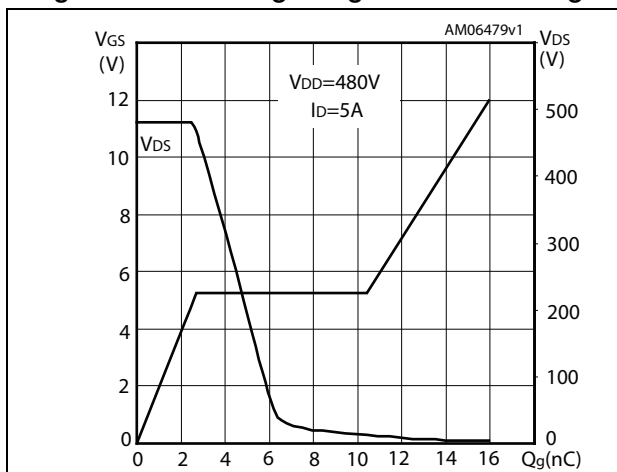


Figure 7. Static drain-source on-resistance

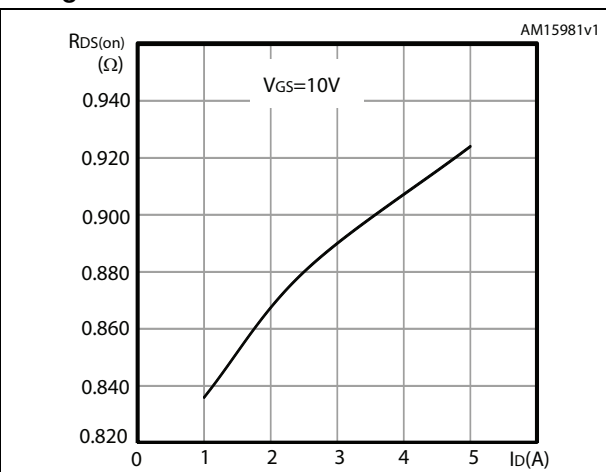


Figure 8. Capacitance variations

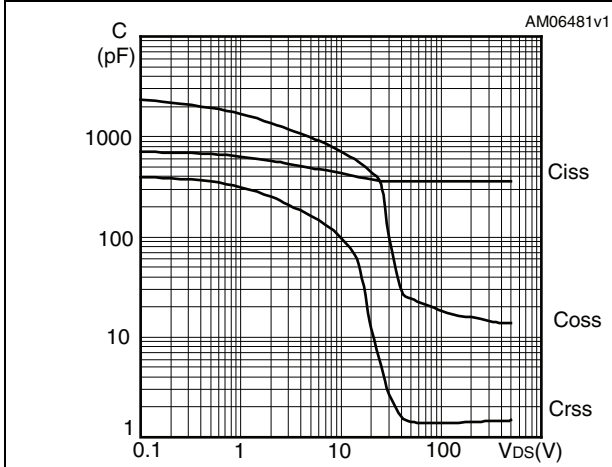


Figure 9. Output capacitance stored energy

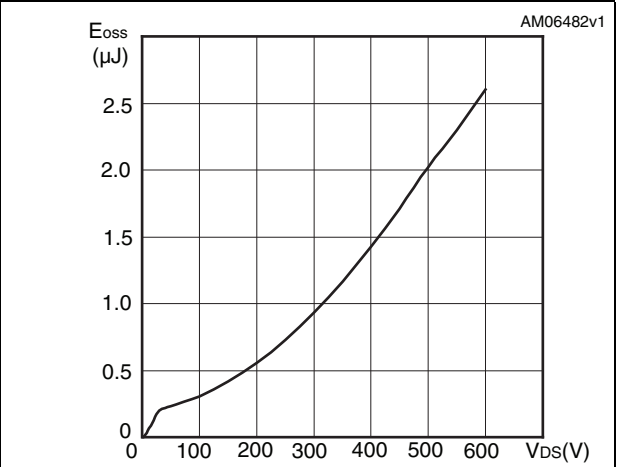


Figure 10. Normalized gate threshold voltage vs temperature

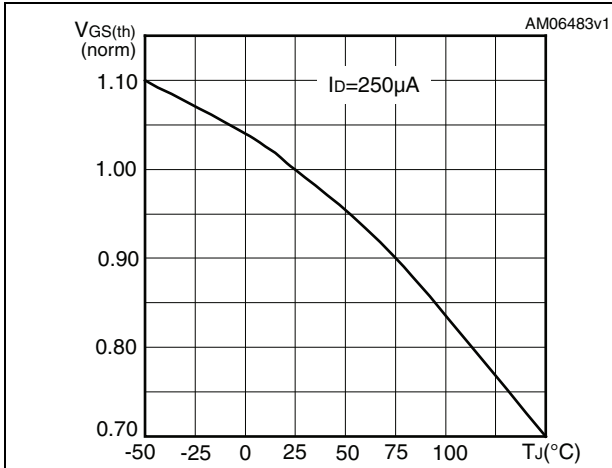


Figure 11. Normalized on-resistance vs temperature

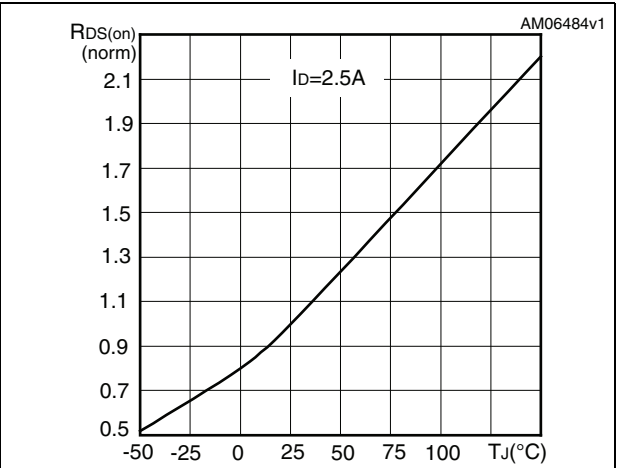
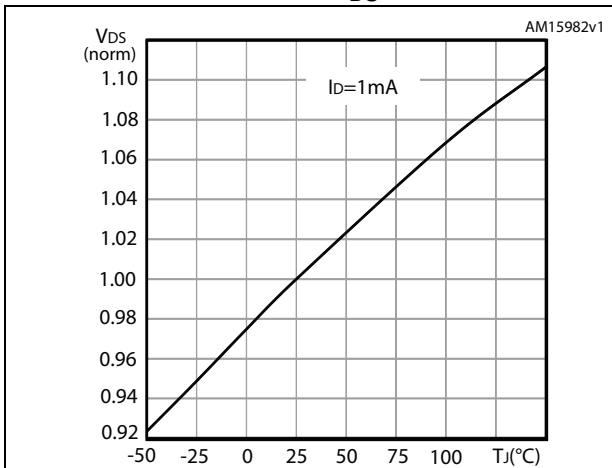


Figure 12. Normalized VDS vs temperature



3 Test circuits

Figure 13. Switching times test circuit for resistive load

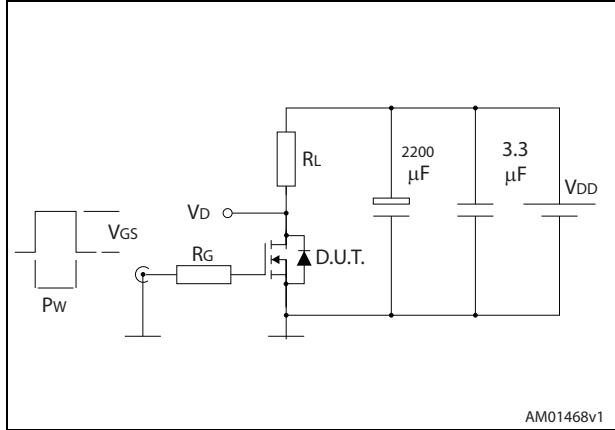


Figure 14. Gate charge test circuit

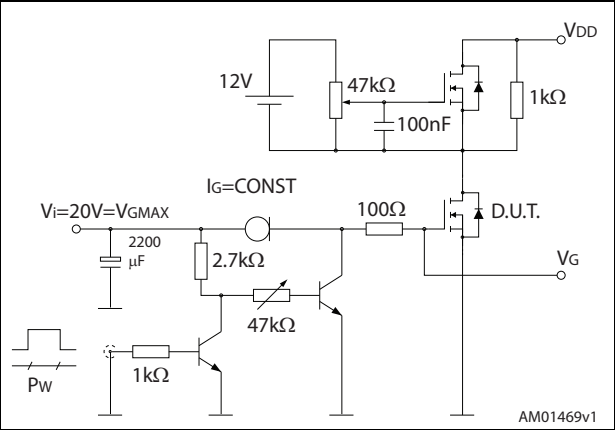


Figure 15. Test circuit for inductive load switching and diode recovery times

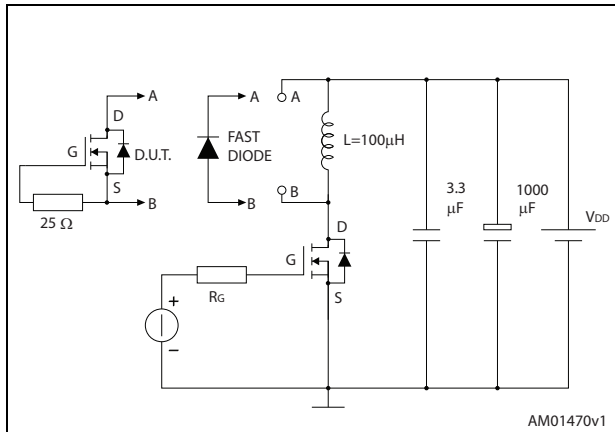


Figure 16. Unclamped inductive load test circuit

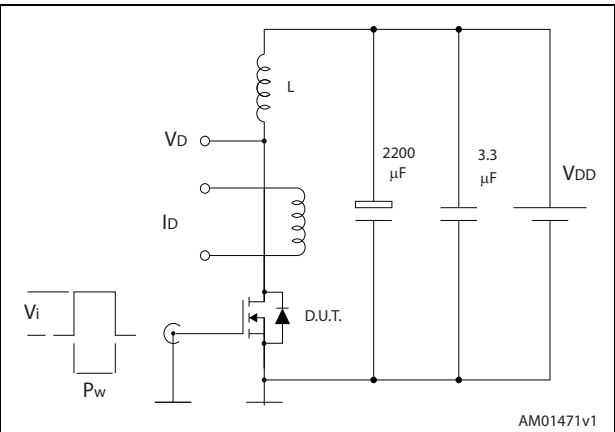


Figure 17. Unclamped inductive waveform

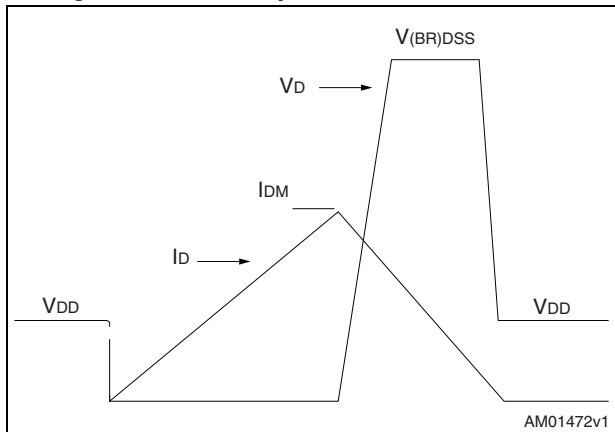
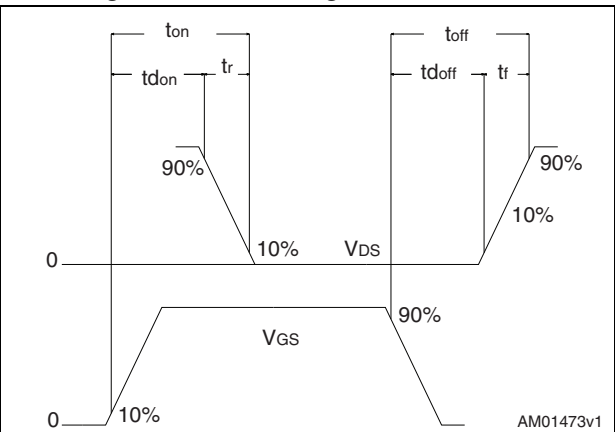


Figure 18. Switching time waveform



4 Package mechanical data

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Table 9. DPAK (TO-252) mechanical data

| Dim. | mm | | |
|------|------|------|-------|
| | Min. | Typ. | Max. |
| A | 2.20 | | 2.40 |
| A1 | 0.90 | | 1.10 |
| A2 | 0.03 | | 0.23 |
| b | 0.64 | | 0.90 |
| b4 | 5.20 | | 5.40 |
| c | 0.45 | | 0.60 |
| c2 | 0.48 | | 0.60 |
| D | 6.00 | | 6.20 |
| D1 | | 5.10 | |
| E | 6.40 | | 6.60 |
| E1 | | 4.70 | |
| e | | 2.28 | |
| e1 | 4.40 | | 4.60 |
| H | 9.35 | | 10.10 |
| L | 1.00 | | 1.50 |
| (L1) | | 2.80 | |
| L2 | | 0.80 | |
| L4 | 0.60 | | 1.00 |
| R | | 0.20 | |
| V2 | 0° | | 8° |

Figure 19. DPAK (TO-252) drawing

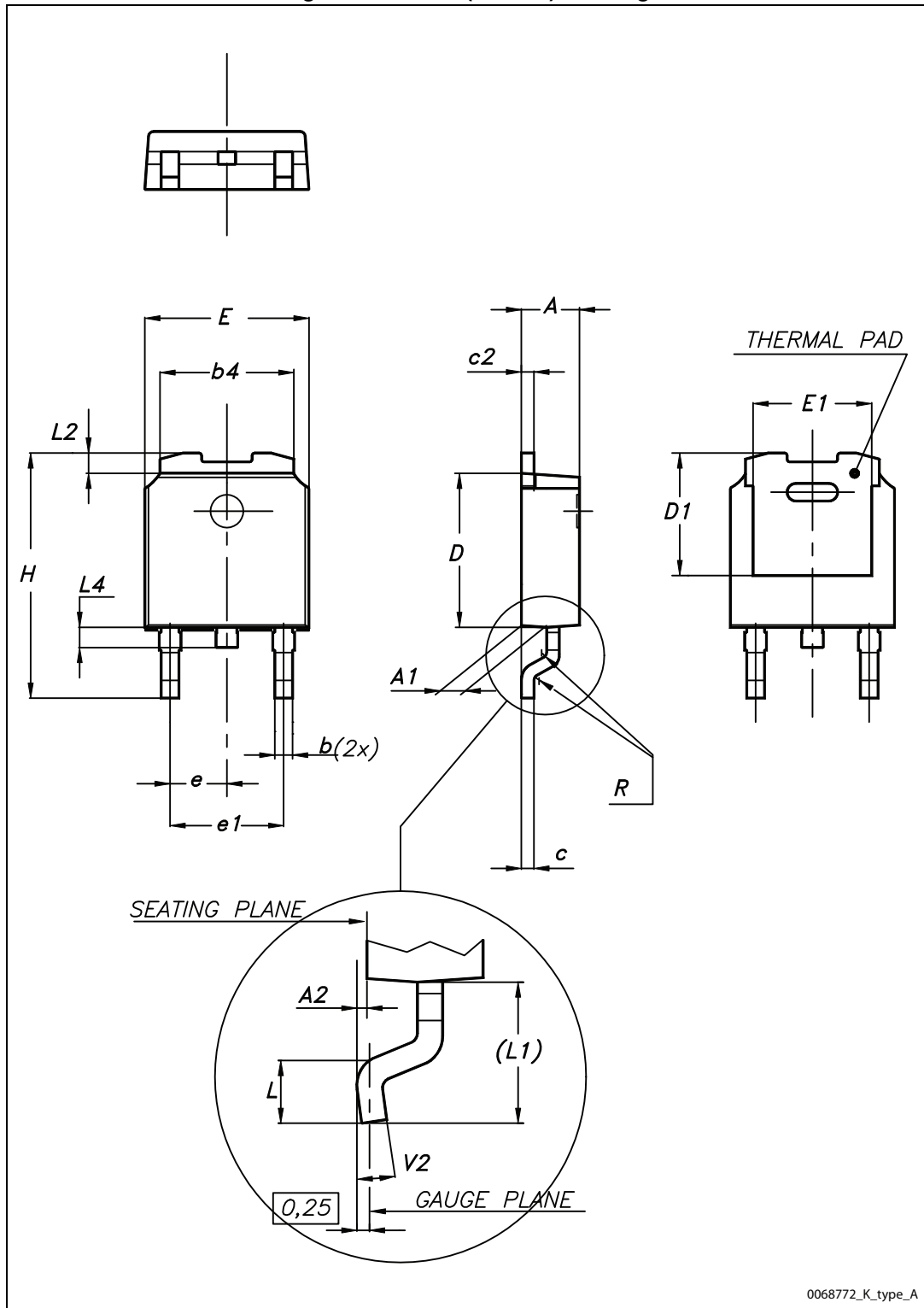
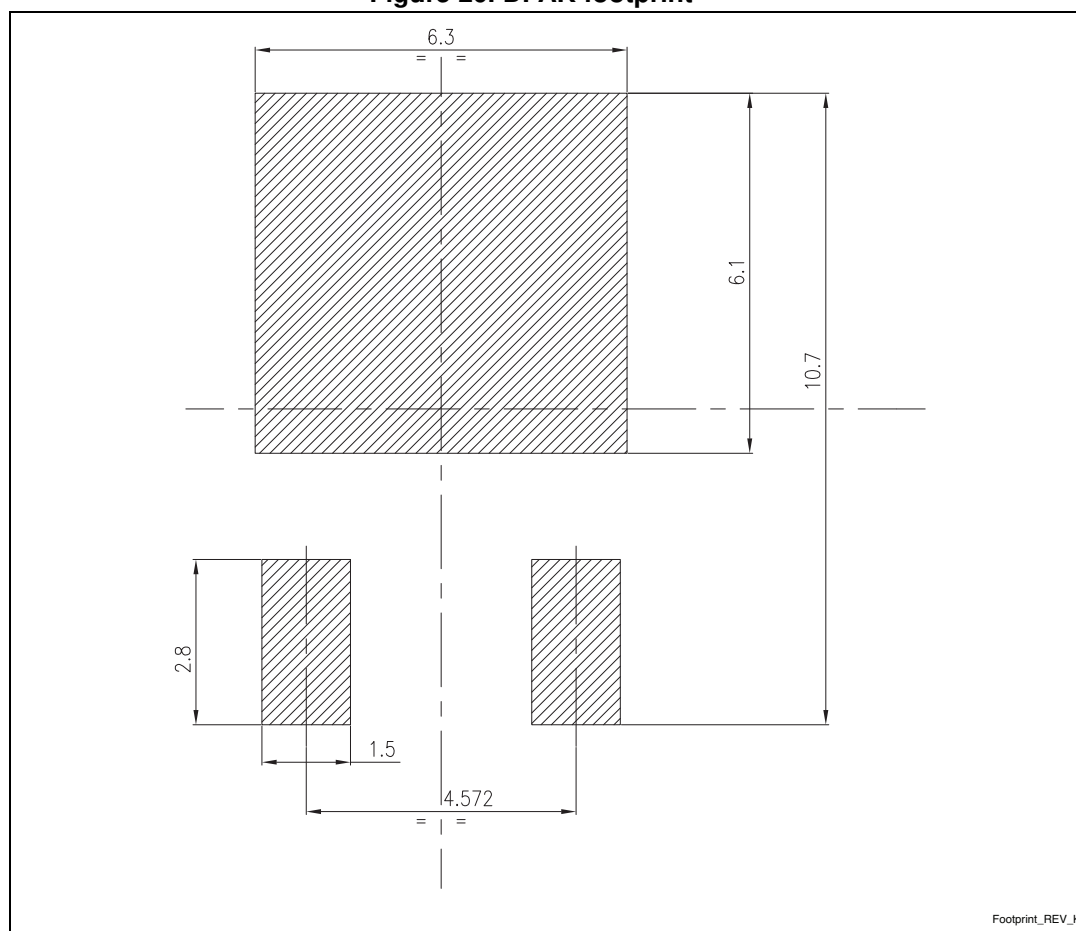


Figure 20. DPAK footprint (a)



a. All dimensions are in millimeters

5 Packaging mechanical data

Table 10. DPAK (TO-252) tape and reel mechanical data

| Tape | | | Reel | | |
|------|------|------|-----------|------|------|
| Dim. | mm | | Dim. | mm | |
| | Min. | Max. | | Min. | Max. |
| A0 | 6.8 | 7 | A | | 330 |
| B0 | 10.4 | 10.6 | B | 1.5 | |
| B1 | | 12.1 | C | 12.8 | 13.2 |
| D | 1.5 | 1.6 | D | 20.2 | |
| D1 | 1.5 | | G | 16.4 | 18.4 |
| E | 1.65 | 1.85 | N | 50 | |
| F | 7.4 | 7.6 | T | | 22.4 |
| K0 | 2.55 | 2.75 | | | |
| P0 | 3.9 | 4.1 | Base qty. | | 2500 |
| P1 | 7.9 | 8.1 | Bulk qty. | | 2500 |
| P2 | 1.9 | 2.1 | | | |
| R | 40 | | | | |
| T | 0.25 | 0.35 | | | |
| W | 15.7 | 16.3 | | | |

Figure 21. Tape for DPAK (TO-252)

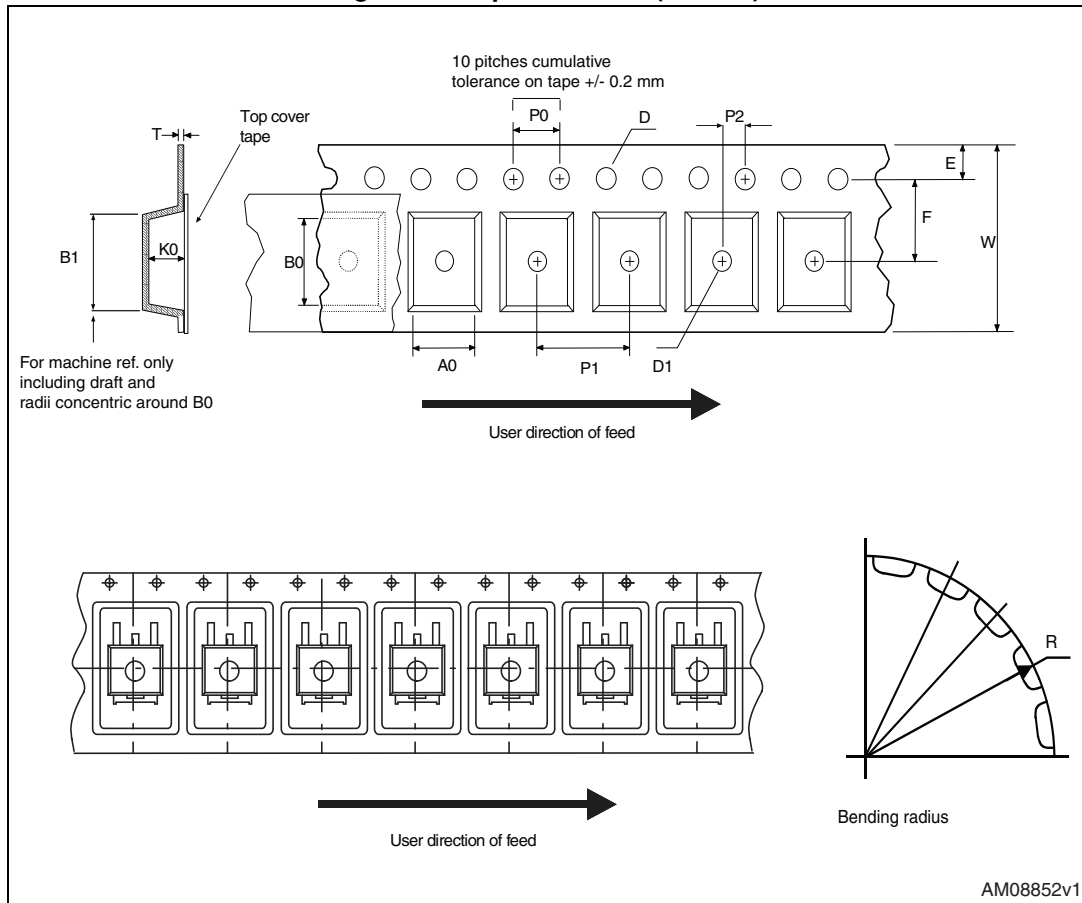
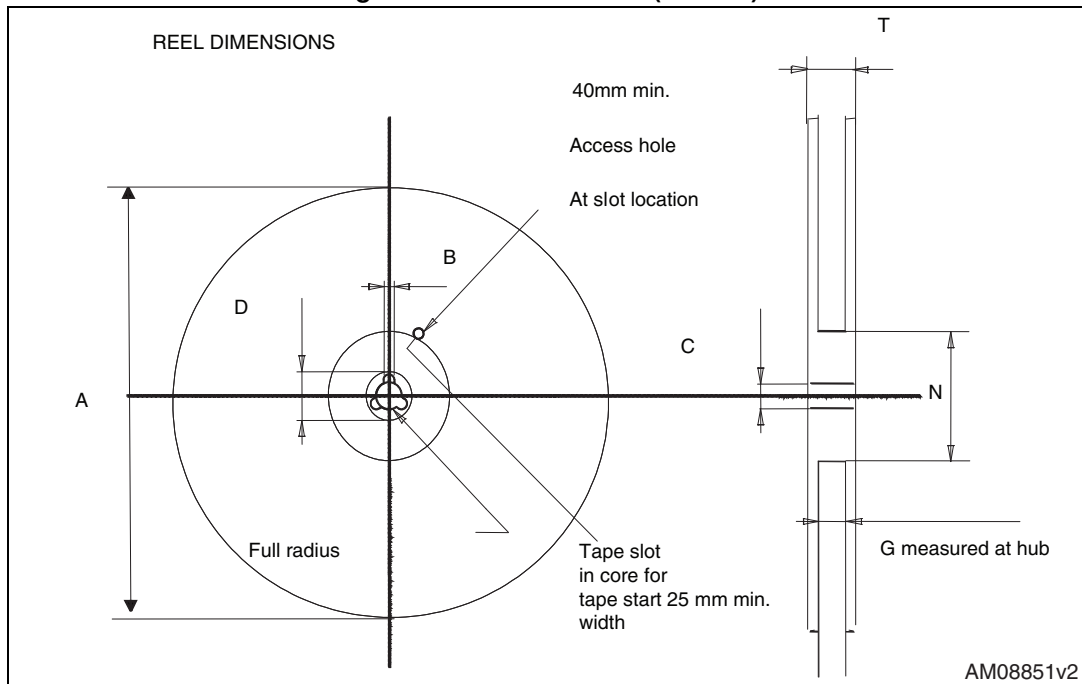


Figure 22. Reel for DPAK (TO-252)



6 Revision history

Table 11. Document revision history

| Date | Revision | Changes |
|-------------|----------|----------------|
| 02-Aug-2013 | 1 | First release. |

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